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ECL Products	

100984

Quad ECL-TTL Translating Transceiver with Registers

FEATURES

- **Typical propagation delay from clock to output: 3.5ns**
- **Typical ECL supply current (-IECL): 110mA**
- **Typical TTL supply current (ITTL): 25mA**
- **Low logic level of ECL output doubles as a high impedance state**
- **ECL output drives 25 Ohm loads**
- **4,000 Volt ESD protection for all pins**
- **Controlled edge rates for quieter bus operation**

DESCRIPTION

The 100984 is a four-bit, translating transceiver with registers. It allows the exchange of data between a 100K ECL

bus and a TTL bus. The A data lines are 100K ECL-compatible and bidirectional. The B data lines are TTL-compatible and unidirectional (BI for input, BO for output). The control lines are 100K ECL-compatible.

There are three basic modes of operation for the device: When data flows from A to BO, an ECL-to-TTL translation occurs. When data flows from BI to A, a TTL-to-ECL translation occurs. Finally, A can be disconnected from B, preventing any data exchange between the ECL and TTL buses.

The 100984 has two storage registers, one for each direction of data flow (A to BO, BI to A). Data is stored on the rising edge of the clock pulse (CPAB, CPBA), provided that the clock enable (CEAB, CEBA) is Low.

Each 100K ECL output (A side) can drive a load as low as 25 Ohms (i.e. a 50 Ohm bus terminated at each end with 50 Ohms to -2.0V). When an ECL output goes Low, its emitter-follower turns off. As a result, the Low logic level approaches the termination voltage (-2.0V) and represents a high impedance state. A High on the ECL output enable (OEBA) will also cut off the emitter-follower, producing the same high impedance state.

The TTL outputs (BO) have three-state capability. A High on the TTL output enable (OEAB) will put the TTL outputs into a high impedance state.

Power may be applied to the VECL and VTTL pins in any order.

All unused inputs can be left open due to integrated pull-down resistors.

ORDERING INFORMATION

DESCRIPTION	ORDER CODE
28-Pin PLCC	100984A

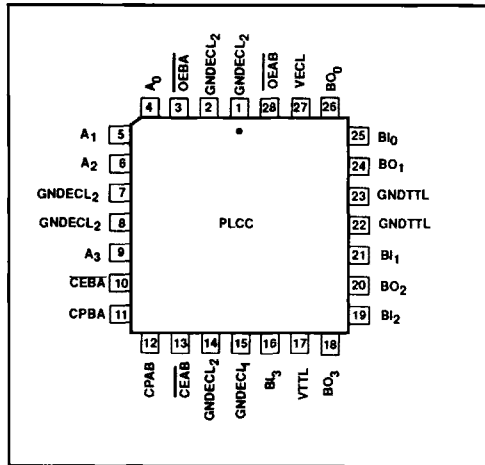
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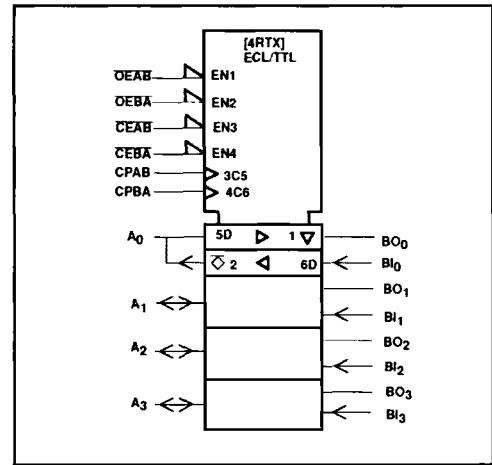
PIN DESCRIPTION

PINS	DESCRIPTION
A ₀ – A ₃	Bidirectional data lines (100K ECL compatible)
BI ₀ – BI ₃	Data inputs (TTL compatible)
BO ₀ – BO ₃	Data outputs (TTL compatible)
OEAB	BO output enable (100K ECL compatible)
OEBA	A output enable (100K ECL compatible)
CPAB	Clock pulse input for A-to-BO data flow (100K ECL compatible)
CPBA	Clock pulse input for BI-to-A data flow (100K ECL compatible)
CEAB	Clock enable input for A-to-BO data flow (100K ECL compatible)
CEBA	Clock enable input for BI-to-A data flow (100K ECL compatible)
VECL	ECL supply voltage
VTTL	TTL supply voltage
GNDECL ₁	Ground for ECL internal logic and reference generator
GNDECL ₂	Ground for ECL outputs
GNDTTL	TTL ground

PIN CONFIGURATION



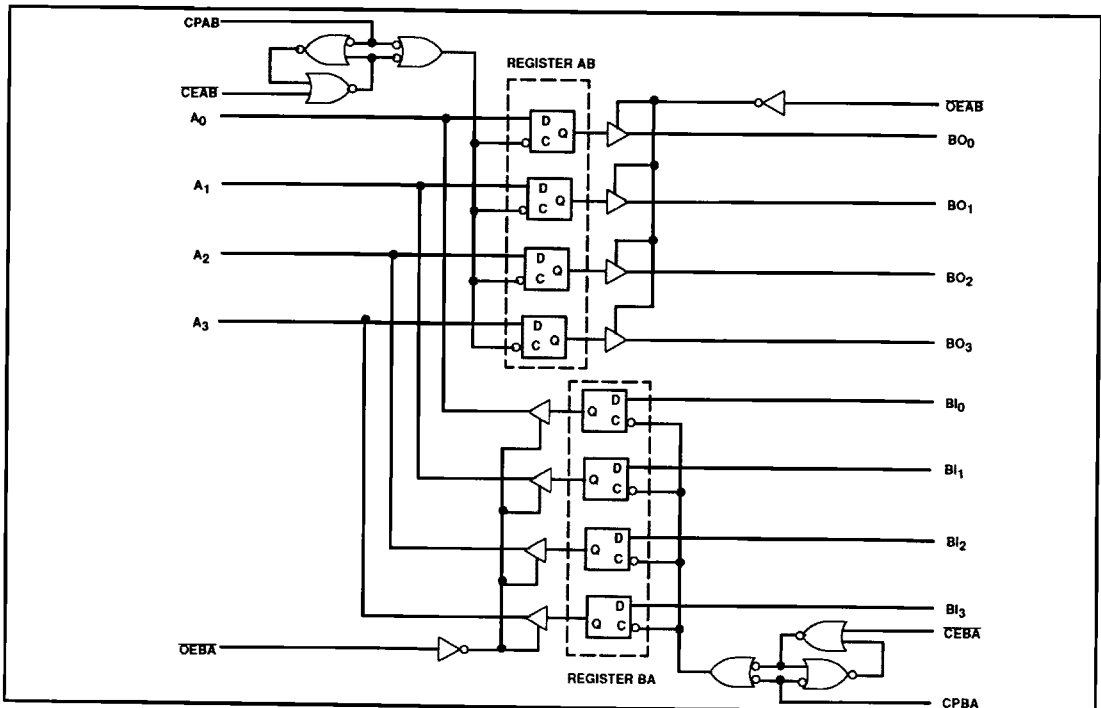
IEC/IEEE SYMBOL



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LOGIC DIAGRAM



NOTE:

Pins BI₀ through BI₃ and BO₀ through BO₃ are TTL-compatible. Pins CPAB, CPBA, CEAB, CEBA, OEAB, OEBA, and A₀ through A₃ are ECL-compatible.

FUNCTION TABLE

ENABLES		CLOCK	INPUT	REGISTER	OUTPUT	OPERATING MODE
OEAB	CEAB	CPAB	A _n	AB	BO _n	A-TO-BO DATA PATH (ECL-TO-TTL TRANSLATION)
OEBA	CEBA	CPBA	BI _n	BA	A _n	BI-TO-A DATA PATH (TTL-TO-ECL TRANSLATION)
L	L	↑	L	L	L	Load data into register and present at outputs
L	L	↑	H	H	H	
L	L	↕	X	L	L	Hold data in register and present at outputs
L	L	↕	X	H	H	
L	H	X	X	L	L	
L	H	X	X	H	H	
H	L	↑	L	L	Z	Load data in register with outputs in high impedance state
H	L	↑	H	H	Z	
H	L	↕	X	NC	Z	Hold data in register with outputs in high impedance state
H	H	X	X	NC	Z	

NOTES:

H = High voltage level
 L = Low voltage level
 X = Don't care
 NC = No change

Z = High impedance state
 ↑ = Low-to-High transition
 ↕ = No Low-to-High transition

Any combination of A-to-B and B-to-A operations may be carried out concurrently, provided that no signal is driven into an active (enabled) output.

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ABSOLUTE MAXIMUM RATINGS FOR ECL-COMPATIBLE LINES $\text{GNDECL}_1 = \text{GNDECL}_2 = \text{GNDTTL} = \text{ground}$
 $T_A = 0^\circ\text{C}$ to $+85^\circ\text{C}$ unless otherwise specified.

SYMBOL	PARAMETER	LIMITS	UNIT
VECL	ECL supply voltage range	-7.0 to +0.5	V
V_{IN}	Input voltage (V_{IN} should never be more negative than VECL)	VECL to +0.5	V
I_{O}	Output source current (continuous)	-100	mA

NOTE:

Operation beyond the limits set forth in this table may impair the useful life of the device.

ABSOLUTE MAXIMUM RATINGS FOR TTL-COMPATIBLE LINES $\text{GNDECL}_1 = \text{GNDECL}_2 = \text{GNDTTL} = \text{ground}$,
 $T_A = 0^\circ\text{C}$ to $+85^\circ\text{C}$ unless otherwise specified.

SYMBOL	PARAMETER	LIMITS	UNIT
VTTL	TTL supply voltage range	-0.5 to +7.0	V
V_{IN}	Input voltage	-0.5 to VTTL	V
I_{IN}	Input current	-30 to +5.0	mA
V_{OUT}	Voltage applied to output in High state	-0.5 to VTTL	V
I_{OUT}	Current applied to output in Low state	+96	mA
T_{S}	Storage temperature range	-65 to +150	$^\circ\text{C}$
T_{J}	Maximum junction temperature	+150	$^\circ\text{C}$

NOTE:

Operation beyond the limits set forth in this table may impair the useful life of the device.

DC OPERATING CONDITIONS FOR ECL-COMPATIBLE LINES

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS			UNIT
			MIN.	NOM.	MAX.	
GNDECL_1	Ground for ECL internal logic and reference generator		0	0	0	V
GNDECL_2	Ground for ECL outputs		0	0	0	V
VECL	ECL supply voltage		-4.8	-4.5	-4.2	V
VECL	ECL supply voltage when operating with the 10K or the 10KH ECL family		-5.7			V
V_{IH}	High level input voltage	VECL = -4.2V	-1150		-880	mV
		VECL = -4.5V	-1165			
		VECL = -4.8V	-1165			
V_{IL}	Low level input voltage	VECL = -4.2V	-1810		-1475	mV
		VECL = -4.5V			-1475	mV
		VECL = -4.8V			-1490	mV

NOTE:

When operating at other than the specified VECL voltages (-4.2V, -4.5V, -4.8V), the DC and AC electrical characteristics will vary slightly from their specified values.

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DC OPERATING CONDITIONS FOR TTL-COMPATIBLE LINES

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN.	NOM.	MAX.	
GNDTTL	TTL ground	0	0	0	V
VTTL	TTL supply voltage	+4.5	+5.0	+5.5	V
V _{IH}	High level input voltage	+2.0			V
V _{IL}	Low level input voltage			+0.8	V
-I _{OH}	High level output current			15	mA
I _{OL}	Low level output current			48	mA
T _A	Operating ambient temperature range	0	+25	+85	°C

DC ELECTRICAL CHARACTERISTICS FOR ECL-COMPATIBLE LINES

GNDECL₁ = GNDECL₂ = GNDTTL = ground, VECL = -4.8V to -4.2V, VTTL = +4.5V to +5.5V, T_A = 0°C to +85°C unless otherwise specified^{1,3,4}

SYMBOL	PARAMETER	TEST CONDITIONS ²	LIMITS			UNIT	
			MIN.	TYP.	MAX.		
V _{OH}	High level output voltage	Store High state in register BA. A _n is tested with a 25Ω load terminated to V _T = -2.0V ± 0.010V. OEBA at V _{ILMIN}	VECL = -4.2V	-1020		-870	mV
			VECL = -4.5V	-1025	-955	-880	mV
			VECL = -4.8V	-1035		-880	mV
V _{OHT}	High level output threshold voltage	Store High state in register BA. A _n is tested with a 25Ω load terminated to V _T = -2.0V ± 0.010V. OEBA at V _{ILMAX}	VECL = -4.2V	-1030			mV
			VECL = -4.5V	-1035			mV
			VECL = -4.8V	-1045			mV
I _{OZ}	Off-state output current ⁵	Store High state in register BA. OEBA and OEAB at V _{IHMAX} . Apply -2.1V to A _n under test.				90	μA
I _{IH}	High level input current ⁵	A _n	A _n under test at V _{IHMAX} , other A _n at V _{ILMIN} . OEBA at V _{IHMAX} .			120	μA
		OEAB, OEBA, CEAB, CEBA, CPAB, CPBA	One control line under test at V _{IHMAX} , all other control lines at V _{ILMIN} . All B _n at V _{ILMIN} . All A _n and B _O _n open.			140	μA
I _{IL}	Low level input current ⁵	A _n	A _n under test at V _{ILMIN} , other A _n at V _{IHMAX} . OEBA at V _{IHMAX} .	10			μA
		OEAB, OEBA, CEAB, CEBA, CPAB, CPBA	One control line under test at V _{ILMIN} , all other control lines at V _{IHMAX} . All B _n at V _{IHMAX} . All A _n and B _O _n open.	10			μA
-IECL	ECL supply current	All A _n at V _{IHMAX} . OEBA at V _{IHMAX} .		64	110	150	mA

NOTES:

- The specified limits represent the worst case values for the parameter. Since these worst case values normally occur at the supply voltage and temperature extremes, additional noise immunity can be achieved by decreasing the allowable operating condition ranges.
- Conditions for testing shown in the tables are not necessarily worst case. For worst case testing guidelines, refer to DC Testing, Chapter 1, Section 3.
- The specified limits shown in the DC electrical characteristics table can be met only after thermal equilibrium has been established. Thermal equilibrium is established by applying power for at least 2 minutes, while maintaining transverse airflow of 2.5 meters/sec (500 linear feet/min) over the device, mounted either in a test socket or on a printed circuit board. Test voltage values are given in the DC operating conditions table.
- The device can function down to VECL = -5.7V, allowing operation with either the 10K or the 10KH family. Correction factors can be used to calculate new DC limits for the extended VECL range. For more information, see Chapter 10, Section 4.
- For bidirectional lines, this parameter includes currents due to output leakage and input pull-down resistors.

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DC ELECTRICAL CHARACTERISTICS FOR TTL-COMPATIBLE LINES

GNDECL₁ = GNDECL₂ = GNDTTL = ground, VECL = -4.8V to -4.2V, VTTL = 4.5V to 5.5V, T_A = 0°C to +85°C unless otherwise specified^{1,3}

SYMBOL	PARAMETER	TEST CONDITIONS ²	LIMITS			UNIT	
			MIN.	TYP.	MAX.		
V _{OH}	High level output voltage	Store High state in register AB. OEAB at V _{ILMIN} .	I _{OH} = -3mA	2.4		V	
			I _{OH} = -15mA	2.0		V	
V _{OL}	Low level output voltage	Store Low state in register AB. OEAB at V _{ILMIN} .	I _{OL} = +24mA		0.35	0.50	V
			I _{OL} = +48mA		0.40	0.55	V
V _{IK}	Input clamp voltage	Apply -18mA to B _{1n} under test with other B _{1n} open.	-1.2	-0.73		V	
I _I	Input current at maximum input voltage	B _{1n} under test at +5.5V, other B _{1n} at ground. VTTL at +5.5V.			500	μA	
I _{IH}	High level input current	B _{1n} under test at +2.4V, other B _{1n} at ground.			70	μA	
-I _{IL}	Low level input current	B _{1n} under test at +0.4V, other B _{1n} at +2.4V.			70	μA	
I _{OZH}	Off-state output current, High level voltage applied	Store Low state in register AB. OEAB and OEBA at V _{IHMAX} . Apply 2.4V to B _{0n} under test.			80	μA	
I _{OZL}	Off-state output current, Low level voltage applied	Store High state in register AB. OEAB and OEBA at V _{IHMAX} . Apply 0.5V to B _{0n} under test.			40	μA	
-I _{OS}	Short circuit output current ⁴	Store High state in register AB. One B _{0n} under test at ground. OEAB at V _{ILMIN} .	60	95	225	mA	
ITTLH	TTL supply current with outputs High	Store High state in register AB. OEAB at V _{ILMIN} . All B _{0n} open. VTTL at +5.5V.		20	30	mA	
ITTL	TTL supply current with outputs Low	Store Low state in register AB. OEAB at V _{ILMIN} . All B _{0n} open. VTTL at +5.5V.		25	35	mA	
ITTLZ	TTL supply current with outputs in the high impedance state	OEAB at V _{IHMAX} . All B _{0n} open. VTTL at +5.5V.		30	40	mA	

NOTES:

- The specified limits represent the worst case values for the parameter. Since these worst case values normally occur at the supply voltage and temperature extremes, additional noise immunity can be achieved by decreasing the allowable operating condition ranges.
- Conditions for testing shown in the tables are not necessarily worst case. For worst case testing guidelines, refer to DC Testing, Chapter 1, Section 3.
- The specified limits shown in the DC electrical characteristics table can be met only after thermal equilibrium has been established. Thermal equilibrium is established by applying power for at least 2 minutes, while maintaining transverse airflow of 2.5 meters/sec (500 linear feet/min) over the device, mounted either in a test socket or on a printed circuit board. Test voltage values are given in the DC operating conditions table.
- Not more than one output should be shorted at a time. The other outputs should not be loaded. For testing I_{OS}, the use of a high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

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AC ELECTRICAL CHARACTERISTICS FOR TTL-TO-ECL DATA FLOW

PLCC GNDECL₁ = GNDECL₂ = GNDTTL = ground, VECL = -5.7V to -4.2V, VTTL = 4.5V to 5.5V.

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS						UNIT
			T _A = 0°C		T _A = +25°C		T _A = +85°C		
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
f _{MAX}	Maximum clock frequency CPBA	Waveform 1	350		350		350		MHz
t _{PZH} t _{PHZ}	Propagation delay CPBA to A _n	Waveform 1	2.0 0.5	4.5 3.0	2.0 0.5	4.5 3.0	2.0 0.5	4.5 3.0	ns ns
t _{PZH}	Output enable time OEBA to A _n	Waveform 3	2.0	4.5	2.0	4.5	2.0	4.5	ns
t _{PHZ}	Output disable time OEBA to A _n	Waveform 3	0.5	2.5	0.5	2.5	0.5	2.5	ns
t _{TZH} t _{THZ}	Transition time for A _n	Waveform 1	0.5 0.5	2.5 2.5	0.5 0.5	2.5 2.5	0.5 0.5	2.5 2.5	ns ns
t _{S(H)} t _{S(L)}	Setup time B _{1n} to CPBA	Waveform 1	3.5 4.0		3.5 4.0		3.5 4.0		ns ns
t _{H(H)} t _{H(L)}	Hold time B _{1n} to CPBA	Waveform 1	0 0		0 0		0 0		ns ns
t _{S(H)} t _{S(L)}	Setup time CEBA to CPBA	Waveform 2	1.0 1.5		1.0 1.5		1.0 1.5		ns ns
t _{H(H)} t _{H(L)}	Hold time CEBA to CPBA	Waveform 2	1.0 1.0		1.0 1.0		1.0 1.0		ns ns
t _{w(H)} t _{w(L)}	Pulse width CPBA	Waveform 1	1.0 1.0		1.0 1.0		1.0 1.0		ns ns

NOTE: For AC test setup information, see AC Testing, Chapter 2, Section 3.

AC ELECTRICAL CHARACTERISTICS FOR ECL-TO-TTL DATA FLOW

PLCC GNDECL₁ = GNDECL₂ = GNDTTL = ground, VECL = -5.7V to -4.2V, VTTL = 4.5V to 5.5V.

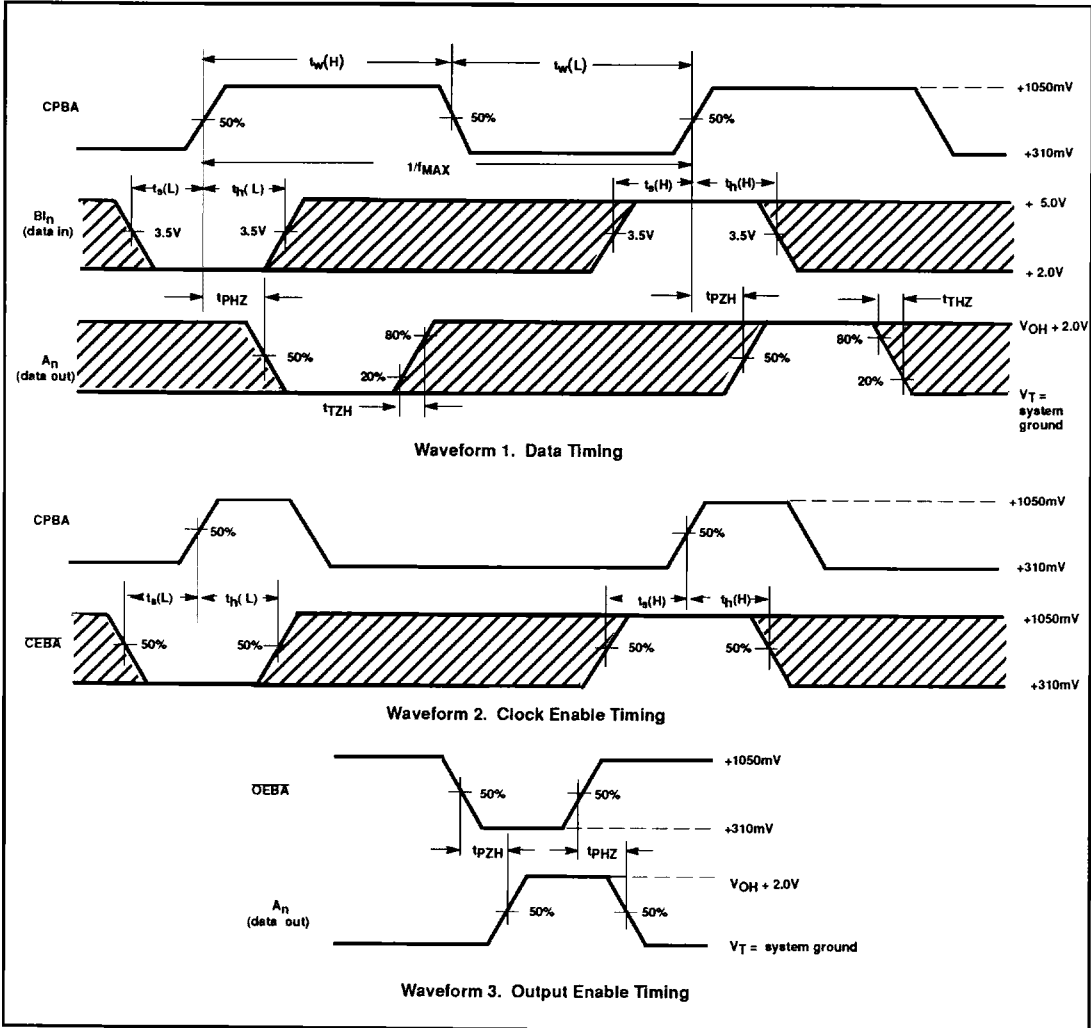
SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS						UNIT
			T _A = 0°C		T _A = +25°C		T _A = +85°C		
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
f _{MAX}	Maximum clock frequency CPAB	Waveform 4	300		300		300		MHz
t _{PLH} t _{PHL}	Propagation delay CPAB to BO _n	Waveform 4	1.5 2.0	4.0 4.5	1.5 2.0	4.0 4.5	1.5 2.0	4.0 4.5	ns ns
t _{PZH} t _{PZL}	Output enable time OEAB to BO _n	Waveform 6	1.5 2.0	4.0 5.0	1.5 2.0	4.0 5.0	1.5 2.0	4.0 5.0	ns ns
t _{PHZ} t _{PLZ}	Output disable time OEAB to BO _n	Waveform 6	2.0 4.0	5.0 7.0	2.0 4.0	5.0 7.0	2.0 4.0	5.0 7.0	ns ns
t _{S(H)} t _{S(L)}	Setup time A _n to CPAB	Waveform 4	1.0 1.0		1.0 1.0		1.0 1.0		ns ns
t _{H(H)} t _{H(L)}	Hold time A _n to CPAB	Waveform 4	1.0 1.0		1.0 1.0		1.0 1.0		ns ns
t _{S(H)} t _{S(L)}	Setup time CEAB to CPAB	Waveform 5	1.0 1.0		1.0 1.0		1.0 1.0		ns ns
t _{H(H)} t _{H(L)}	Hold time CEAB to CPAB	Waveform 5	1.0 1.5		1.0 1.5		1.0 1.5		ns ns
t _{w(H)} t _{w(L)}	Pulse width CPAB	Waveform 4	1.0 1.0		1.0 1.0		1.0 1.0		ns ns

NOTE: For AC test setup information, see AC Testing, Chapter 2, Section 3.

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AC WAVEFORMS FOR TTL-TO-ECL DATA FLOW

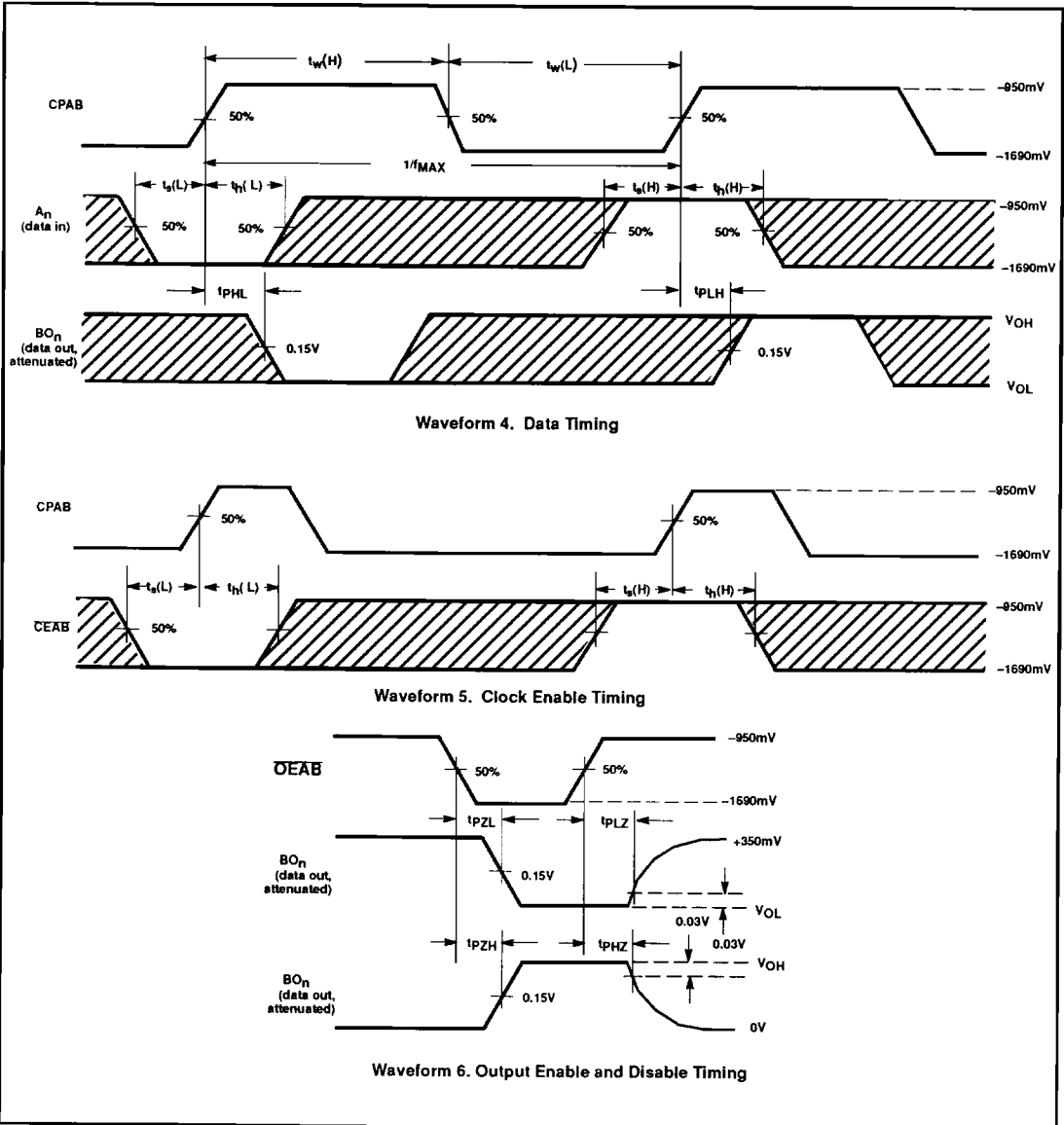


NOTE:
All power and signal voltages shifted up 2.0V for AC bench test purposes.

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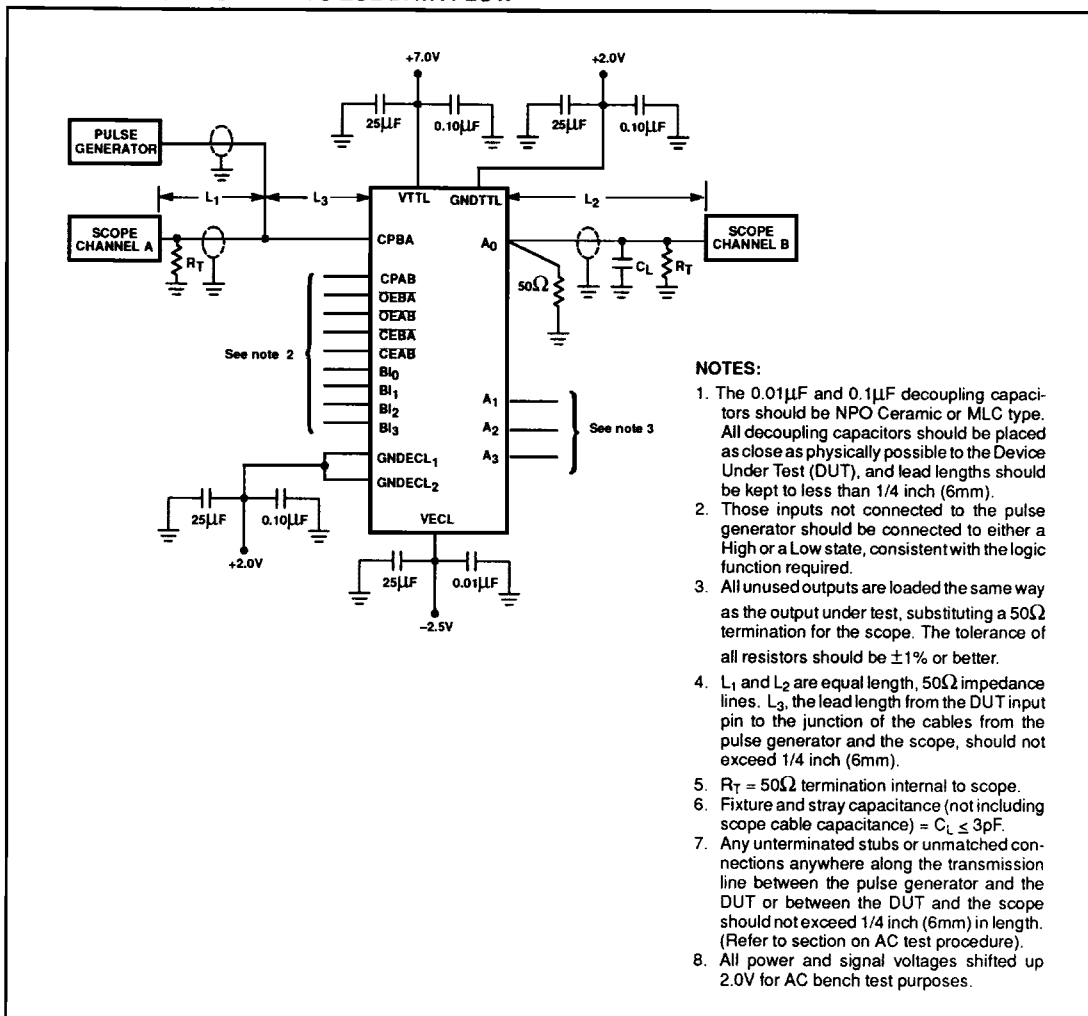
AC WAVEFORMS FOR ECL-TO-TTL DATA FLOW



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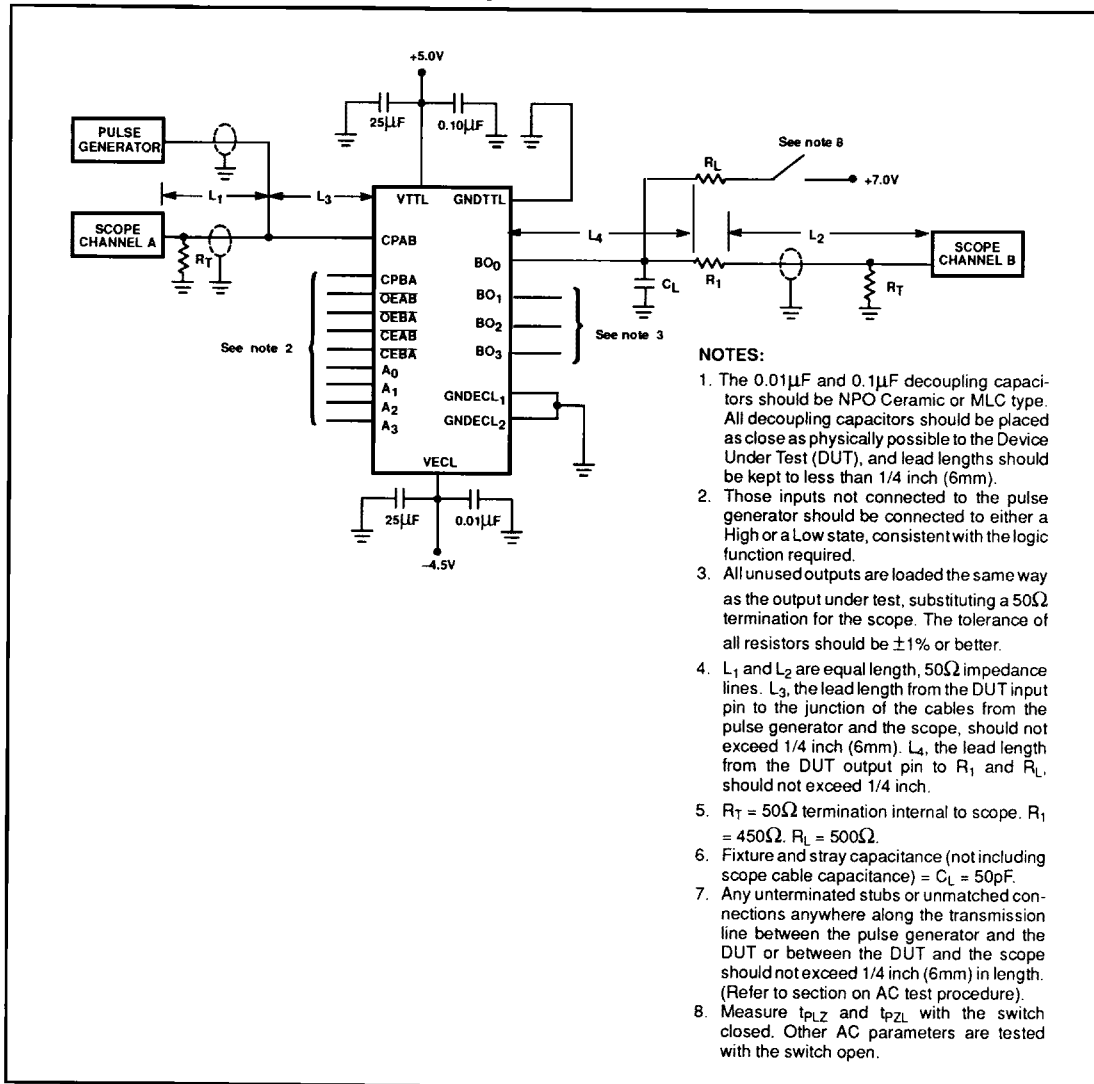
AC TEST CIRCUIT FOR TTL-TO ECL DATA FLOW



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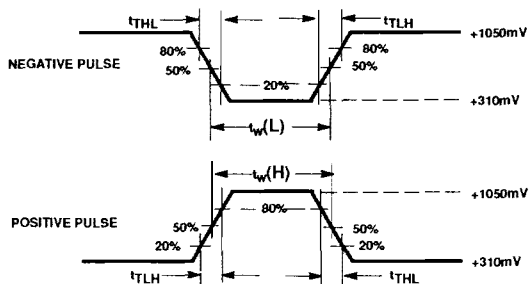
AC TEST CIRCUIT FOR ECL-TO TTL DATA FLOW



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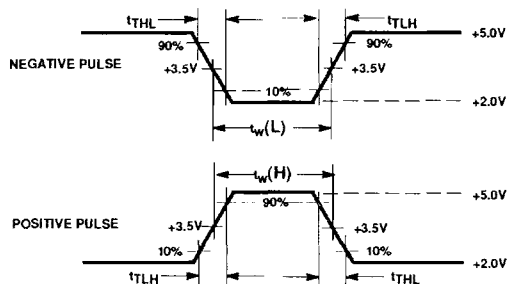
INPUT PULSE DEFINITION FOR TTL-TO-ECL DATA FLOW



**INPUT PULSE REQUIREMENTS FOR
CPAB, CPBA, CEAB, CEBA, OEAB, OEBA**

GNDECL₁ = GNDECL₂ = GNDTTL = +2.0V ± 0.010V,
VECL = -2.8V to -2.2V, VTTL = +6.5V to +7.5V, V_I = 0V (system ground)

Family	Amplitude	Rep Rate	t _w (L), t _w (H)	t _{TLH} , t _{THL}
100K ECL	740mV _{p-p}	1MHz	500ns	0.7 ± 0.1ns



INPUT PULSE REQUIREMENTS FOR Bi_T

GNDECL₁ = GNDECL₂ = GNDTTL = +2.0V ± 0.010V,
VECL = -2.8V to -2.2V, VTTL = +6.5V to +7.5V, V_I = 0V (system ground)

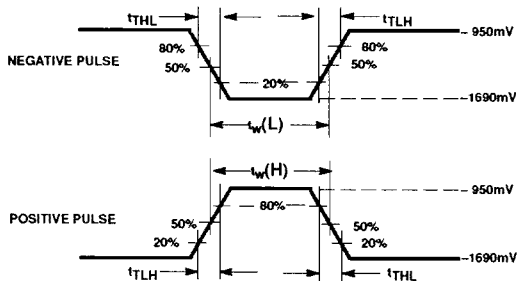
Family	Amplitude	Rep Rate	t _w (L), t _w (H)	t _{TLH} , t _{THL}
TTL	3.0V _{p-p}	1MHz	500ns	2.5 ± 0.2ns

NOTE:
All power and signal voltages shifted up 2.0V for AC bench test purposes.

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INPUT PULSE DEFINITION FOR ECL-TO-TTL DATA FLOW



INPUT PULSE REQUIREMENTS FOR A _n , CPAB, CPBA, CEAB, CEBA, OEAB, OEBA GNDECL ₁ = GNDECL ₂ = GNDTTL = 0V (system ground), VECL = -4.8V to -4.2V, VTTL = +4.5V to +5.5V				
Family	Amplitude	Rep Rate	$t_w(L), t_w(H)$	t_{TLH}, t_{THL}
100K ECL	740mV _{p-p}	1MHz	500ns	0.7 ± 0.1 ns